

Qualification Results Summary of ADGM1004 Revision

Qualification data supports the PCN of ADGM1304 and ADGM1004 generics

QUALIFICATION RESULTS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JS-002</i>	3/voltage	Pass
Electrostatic Discharge <i>Human Body Model</i>	JEDEC <i>JS-001-2010</i>	3/voltage	Pass
Latch-up	JEDEC <i>JESD78</i>	1 x 15	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3 x 11	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	3 x 77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3 x 77	Pass
High Temperature Operating Life (HTOL) – Toggle Mode	JEDEC <i>JESD22-A108</i>	3 x 77	Pass
High Temperature Operating Life (HTOL) – Hold Down Mode	JEDEC <i>JESD22-A108</i>	3 x 77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3 x 77	Pass

*These samples were subjected to preconditioning (per J-STD-020 Level 3) prior to the start of the stress test. Level 3 preconditioning consists of the following: 1. Bake – 24 hours at 125°C; 2. Soak – unbiased soak for 192 hours at 30°C, 60%RH; 3. Reflow – three passes through a reflow oven with a peak temperature of 260°C.